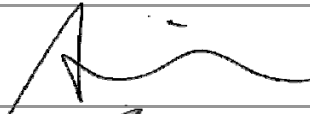




**Product/Process Change Notification**

PCN#	Effective Date	Issue Date
2014-08-01C-11	2015/2/1	2014/8/1
PCN Classification	Product Category	
Major	SOT-23 Package	
Subject		
Add a molding vendor		
Affected Product(s)		
As attachment		
Description of Change(s)		
In order to avoid shortage of the material, and enhance the speed of delivery, thus, we add a new vendor.		
Content of Change(s)		
Add Molding vendor--ELER-8-100HFE		
Impact(s)		
N/A		
Attachment(s)		
Reliability Teat Report.		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website <http://www.secosgmbh.com>

Affected Product

SCS344K	BAV99	2SA1015K	2N7002K	KTD1304
SCS491D	BAW56	2SA1036	S2N7002	M28S
BAT54	BAV70	2SA1037	S2N7002K	M8050
BAT54A	SCS217K	2SA1162	SMS2020	M8550
BAT54C	BAV89	2SA1179	SMS2310	MMBT2222A
BAT54S	MMBD4148	2SA1235A	SMS2333	MMBT2907
MDL301K	BAS116	2SA1298	SMS318	MMBT2907A
SCS230D	BAS16	2SA733	BC846B	MMBT3904
BAS40	SCS190K	2SA812K	BC847A	MMBT3906
BAS40-04	SCS196K	2SB1116	BC847B	MMBT4401
BAS40-05	SCS202NK	2SB1197	BC847C	MMBT4403
BAS40-06	SCS202PK	2SB624	BC848A	MMBT491
SCS495D	SZMD05C	2SB709A	BC848B	MMBT493
BAS70	SZMD07C	2SC1623K	BC848C	MMBT5401
BAS70-04	SZMD12C	2SC1654	BC856A	MMBT5551
BAS70-05	BAS21A	2SC2411	BC856B	MMBT589
BAS70-06	BAS21C	2SC2412	BC857A	SS8050
BAV23A	BAS21S	2SC2712	BC857B	SS8550
BAV23C	MMBD318A	2SC2714	BC857C	DTA114ECA
BAV23S	MMBD318C	2SC2715	BC858A	DTA114TCA
SCS2838	MMBD318S	2SC2859	BC858B	DTA114YCA
BAV74	BAP64W-04	2SC3052	BC858C	DTA123JCA
SCS2836	BAP64W-05	2SC5343	MMBTA06	DTA123YCA
BAL99	BAP64W-06	2SC5344	MMBTA13	DTA124ECA
BAV199	SZMD03C	2SC5345	MMBTA14	DTA143ECA
SCS187K	SZMD15C	2SD1781	MMBTA42	DTA143TCA
SCS181K	SZMD24C	2SD2114	MMBTA43	DTA143XCA
MMBD914	SCS226K	2SD2142	MMBTA44	DTA143ZCA
MMBD7000	SCS184K	2SD596	MMBTA55	DTA144ECA
MMBD4448	SCS193K	2SD601A	MMBTA56	DTA144TCA
MMBD248	BZD84Cxxx Series	2SD602	MMBTA92	DTC113ZCA
MMBD248A	BZX84Bxxx Series	2SD602A	MMBTA94	DTC114ECA
MMBD248C	MMBZ52xxB Series	BC807-16	MMBTH10	DTC114TCA
MMBD248S	SMS3415	BC807-25	S8050	DTC114WCA
BAS19	SMS4003K	BC807-40	S8550	DTC114YCA
MMBD1501A	SMS501DE	KTA1504	S9012	DTC123JCA
MMBD1503A	SMS6001	KTA1505	S9013	DTC123YCA
MMBD1504A	SMS840	KTC3265	S9014	DTC124ECA
MMBD1505A	SMS3400A	KTC3875	S9015	DTC143ECA
BAS21	SMS3401A	KTC3876	S9018	DTC143TCA
BC808	BCX19	BCV27	MMBT591	DTC143XCA
BC817-16	BCX70J	BCW61B	MMBT593	DTC143ZCA
BC817-25	BCX70K	BCW61C	MMBT619	DTC144ECA
BC817-40	BFS20	BCW66F	MMBT720	DTC144TCA
BC846A	C1815	BCW66G	MMBTA05	
BCW68	C945	BCW66H	KTC3879	



## Reliability Testing Summary Report

Date: 2014/06/30

Document No.: SH14 -06- 35

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	BAS16	100 ± 5°C, 100% VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	BAS16	150°C, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	BAS16	121°C, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	BAS16	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	BAS16	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	BAS16	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	BAS16	245 ± 5°C, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

**Judgment:**

qualified     unqualified

Testing Start Date: 2014.05.05    Testing End Date: 2014.06.30

Tester: Leo Hsia    Approval: Peter Yang



## Electrical Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
1	745.3mV	119.4V	0.019uA
2	748.7mV	127.1V	0.026uA
3	748.1mV	129.4V	0.033uA
4	746.2mV	117.8V	0.008uA
5	748.5mV	127.4V	0.004uA
6	746.5mV	118.6V	0.014uA
7	747.8mV	129.3V	0.020uA
8	748.9mV	129.4V	0.018uA
9	745.3mV	131.6V	0.033uA
10	750.3mV	123.6V	0.023uA
11	749.2mV	130.7V	0.030uA
12	745.2mV	118.9V	0.020uA
13	747.3mV	130.3V	0.027uA
14	749.3mV	117.5V	0.002uA
15	747.7mV	118.6V	0.007uA
16	745.9mV	121.4V	0.021uA
17	750.2mV	132.2V	0.030uA
18	746.5mV	120.8V	0.008uA
19	749.3mV	117.8V	0.038uA
20	747.9mV	119.5V	0.009uA
21	749.4mV	119.6V	0.026uA
22	746.6mV	130.8V	0.003uA
23	746.1mV	124.4V	0.021uA
24	749.6mV	125.3V	0.004uA
25	745.9mV	129.9V	0.040uA
26	747.3mV	128.8V	0.016uA
27	749.5mV	127.9V	0.028uA
28	749.8mV	130.0V	0.023uA
29	746.5mV	128.7V	0.035uA
30	749.8mV	117.4V	0.008uA
31	749.9mV	118.9V	0.009uA



## Electrical Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
32	750.4mV	126.6V	0.023uA
33	747.6mV	126.7V	0.020uA
34	747.0mV	125.7V	0.035uA
35	747.8mV	121.4V	0.044uA
36	746.2mV	124.6V	0.028uA
37	748.6mV	124.1V	0.032uA
38	746.0mV	126.0V	0.009uA
39	749.9mV	125.8V	0.018uA
40	749.9mV	129.0V	0.020uA
41	747.6mV	129.3V	0.012uA
42	745.6mV	130.0V	0.004uA
43	749.2mV	121.6V	0.022uA
44	747.5mV	133.1V	0.037uA
45	746.5mV	118.8V	0.022uA
46	747.5mV	132.7V	0.043uA
47	747.3mV	117.5V	0.041uA
48	750.1mV	118.7V	0.043uA
49	748.0mV	118.3V	0.036uA
50	749.5mV	119.1V	0.036uA
51	748.6mV	130.8V	0.007uA
52	746.8mV	131.3V	0.006uA
53	747.1mV	126.4V	0.006uA
54	748.4mV	119.9V	0.032uA
55	746.9mV	129.8V	0.041uA
56	748.3mV	119.1V	0.042uA
57	747.0mV	132.0V	0.006uA
58	748.4mV	131.1V	0.029uA
59	746.3mV	129.1V	0.021uA
60	746.9mV	117.1V	0.007uA
61	745.7mV	120.8V	0.003uA
62	746.1mV	130.2V	0.033uA



## Electrical Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
63	746.6mV	117.6V	0.034uA
64	748.0mV	124.2V	0.042uA
65	747.0mV	122.2V	0.041uA
66	746.8mV	131.8V	0.017uA
67	746.3mV	121.0V	0.025uA
68	749.2mV	118.8V	0.036uA
69	750.3mV	131.3V	0.031uA
70	747.5mV	122.5V	0.006uA
71	749.2mV	128.1V	0.016uA
72	748.8mV	122.7V	0.029uA
73	746.0mV	132.2V	0.044uA
74	745.9mV	117.2V	0.038uA
75	747.9mV	118.2V	0.010uA
76	746.0mV	117.3V	0.021uA
77	746.1mV	117.1V	0.014uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temperature Reverse Bias Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	750mV	118.1V	0.024uA	746mV	125.8V	0.004uA
2	746mV	117.6V	0.032uA	747mV	130.1V	0.002uA
3	748mV	130.2V	0.037uA	746mV	117.4V	0.033uA
4	748mV	129.5V	0.020uA	748mV	119.4V	0.015uA
5	746mV	123.9V	0.022uA	747mV	129.4V	0.034uA
6	746mV	122.6V	0.004uA	747mV	131.7V	0.033uA
7	750mV	122.4V	0.005uA	749mV	130.7V	0.040uA
8	746mV	122.7V	0.017uA	748mV	118.0V	0.024uA
9	749mV	117.9V	0.031uA	750mV	132.7V	0.003uA
10	747mV	119.5V	0.032uA	749mV	131.1V	0.044uA
11	746mV	127.4V	0.027uA	748mV	121.4V	0.004uA
12	746mV	124.9V	0.013uA	749mV	131.8V	0.012uA
13	750mV	129.7V	0.004uA	748mV	133.0V	0.011uA
14	747mV	128.4V	0.014uA	748mV	131.6V	0.014uA
15	749mV	131.9V	0.011uA	746mV	123.7V	0.006uA
16	750mV	118.3V	0.035uA	745mV	129.8V	0.041uA
17	747mV	127.4V	0.037uA	746mV	131.4V	0.017uA
18	747mV	118.8V	0.010uA	748mV	130.7V	0.037uA
19	749mV	118.8V	0.044uA	746mV	125.8V	0.012uA
20	747mV	128.4V	0.039uA	750mV	122.4V	0.016uA
21	750mV	129.7V	0.006uA	750mV	123.1V	0.022uA
22	750mV	128.8V	0.033uA	749mV	128.0V	0.021uA
23	747mV	129.4V	0.033uA	748mV	126.6V	0.021uA
24	748mV	121.6V	0.019uA	746mV	120.9V	0.019uA
25	748mV	126.5V	0.005uA	747mV	121.5V	0.043uA
26	748mV	132.0V	0.015uA	748mV	132.5V	0.032uA
27	746mV	132.0V	0.008uA	746mV	129.0V	0.030uA
28	748mV	126.9V	0.017uA	748mV	123.4V	0.017uA
29	746mV	123.3V	0.033uA	746mV	126.9V	0.015uA
30	750mV	129.3V	0.025uA	748mV	129.5V	0.037uA



## High Temperature Reverse Bias Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	747mV	125.7V	0.011uA	747mV	123.4V	0.007uA
32	749mV	126.6V	0.016uA	746mV	129.8V	0.044uA
33	747mV	122.9V	0.019uA	749mV	123.4V	0.005uA
34	746mV	128.4V	0.014uA	749mV	121.9V	0.008uA
35	749mV	131.3V	0.007uA	745mV	117.0V	0.027uA
36	750mV	128.3V	0.041uA	750mV	133.1V	0.020uA
37	745mV	119.3V	0.011uA	748mV	125.4V	0.009uA
38	746mV	121.9V	0.020uA	749mV	132.7V	0.039uA
39	749mV	124.2V	0.019uA	748mV	130.2V	0.025uA
40	747mV	119.7V	0.034uA	746mV	128.2V	0.003uA
41	748mV	122.4V	0.026uA	747mV	130.6V	0.043uA
42	750mV	125.2V	0.009uA	750mV	121.9V	0.033uA
43	749mV	128.2V	0.043uA	750mV	133.2V	0.029uA
44	748mV	126.4V	0.033uA	746mV	120.7V	0.034uA
45	749mV	117.5V	0.031uA	747mV	121.8V	0.013uA
46	746mV	120.5V	0.002uA	749mV	129.2V	0.010uA
47	746mV	131.9V	0.026uA	746mV	133.2V	0.043uA
48	748mV	122.4V	0.022uA	748mV	128.1V	0.042uA
49	747mV	130.5V	0.016uA	748mV	123.6V	0.041uA
50	746mV	119.6V	0.041uA	749mV	125.1V	0.032uA
51	745mV	121.3V	0.025uA	747mV	122.4V	0.040uA
52	747mV	129.5V	0.029uA	748mV	119.2V	0.045uA
53	747mV	131.3V	0.032uA	747mV	118.1V	0.038uA
54	748mV	121.3V	0.013uA	747mV	126.0V	0.039uA
55	748mV	125.7V	0.019uA	750mV	123.0V	0.014uA
56	748mV	131.6V	0.042uA	745mV	117.2V	0.027uA
57	747mV	132.2V	0.023uA	746mV	117.0V	0.007uA
58	748mV	119.8V	0.044uA	748mV	119.5V	0.025uA
59	748mV	128.0V	0.027uA	747mV	123.5V	0.035uA
60	746mV	119.3V	0.042uA	745mV	123.4V	0.017uA





## High Temperature Reverse Bias Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	746mV	124.8V	0.032uA	747mV	124.4V	0.011uA
62	749mV	129.2V	0.011uA	749mV	129.6V	0.033uA
63	747mV	120.8V	0.026uA	749mV	124.2V	0.013uA
64	746mV	121.9V	0.032uA	750mV	125.1V	0.014uA
65	748mV	130.1V	0.044uA	747mV	128.6V	0.034uA
66	747mV	118.1V	0.016uA	747mV	124.0V	0.033uA
67	748mV	132.8V	0.025uA	749mV	120.0V	0.028uA
68	750mV	124.1V	0.004uA	746mV	132.6V	0.044uA
69	750mV	118.0V	0.016uA	749mV	119.6V	0.027uA
70	746mV	124.0V	0.034uA	750mV	131.3V	0.033uA
71	746mV	130.5V	0.008uA	748mV	128.7V	0.010uA
72	746mV	117.4V	0.017uA	749mV	119.1V	0.025uA
73	748mV	117.6V	0.019uA	748mV	119.5V	0.021uA
74	746mV	127.7V	0.010uA	746mV	127.3V	0.035uA
75	747mV	123.6V	0.004uA	750mV	119.3V	0.037uA
76	745mV	130.6V	0.034uA	746mV	131.5V	0.033uA
77	747mV	121.5V	0.020uA	748mV	131.9V	0.040uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temperature Storage Life Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	750mV	125.3V	0.021uA	749mV	123.6V	0.013uA
2	748mV	119.1V	0.027uA	747mV	132.3V	0.013uA
3	745mV	124.3V	0.005uA	746mV	120.4V	0.014uA
4	748mV	126.2V	0.021uA	748mV	120.4V	0.002uA
5	750mV	121.6V	0.016uA	745mV	125.8V	0.030uA
6	747mV	131.5V	0.027uA	745mV	117.5V	0.009uA
7	750mV	122.0V	0.012uA	746mV	131.5V	0.034uA
8	747mV	129.9V	0.044uA	750mV	130.9V	0.044uA
9	750mV	124.8V	0.036uA	750mV	118.7V	0.036uA
10	748mV	117.7V	0.037uA	746mV	117.1V	0.021uA
11	750mV	123.1V	0.026uA	746mV	128.8V	0.036uA
12	746mV	128.6V	0.034uA	748mV	119.5V	0.008uA
13	749mV	118.3V	0.039uA	749mV	126.2V	0.024uA
14	748mV	120.4V	0.016uA	747mV	124.4V	0.031uA
15	750mV	125.3V	0.044uA	746mV	121.5V	0.017uA
16	747mV	119.2V	0.015uA	749mV	130.6V	0.032uA
17	748mV	129.3V	0.004uA	747mV	130.7V	0.016uA
18	747mV	130.9V	0.042uA	750mV	132.5V	0.006uA
19	750mV	118.7V	0.010uA	745mV	133.0V	0.034uA
20	746mV	122.6V	0.015uA	750mV	132.0V	0.013uA
21	746mV	119.3V	0.036uA	747mV	129.0V	0.023uA
22	746mV	129.5V	0.036uA	748mV	123.9V	0.008uA
23	750mV	127.7V	0.034uA	747mV	130.3V	0.029uA
24	748mV	126.4V	0.018uA	748mV	131.4V	0.021uA
25	746mV	126.8V	0.023uA	750mV	124.0V	0.027uA
26	747mV	122.5V	0.010uA	746mV	125.5V	0.045uA
27	748mV	124.3V	0.007uA	747mV	132.4V	0.022uA
28	747mV	119.6V	0.011uA	750mV	118.8V	0.014uA
29	747mV	126.5V	0.015uA	747mV	127.8V	0.042uA
30	748mV	124.6V	0.038uA	747mV	121.3V	0.038uA



## High Temperature Storage Life Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	746mV	126.4V	0.011uA	746mV	131.6V	0.044uA
32	747mV	130.4V	0.037uA	747mV	119.0V	0.024uA
33	750mV	120.7V	0.043uA	750mV	133.1V	0.033uA
34	750mV	130.4V	0.015uA	747mV	126.5V	0.027uA
35	748mV	121.2V	0.010uA	746mV	130.1V	0.029uA
36	748mV	124.5V	0.003uA	749mV	123.6V	0.006uA
37	750mV	124.6V	0.006uA	749mV	120.9V	0.034uA
38	748mV	131.5V	0.034uA	749mV	125.6V	0.040uA
39	750mV	122.6V	0.039uA	750mV	123.1V	0.033uA
40	750mV	119.0V	0.034uA	745mV	118.6V	0.007uA
41	745mV	130.1V	0.021uA	749mV	129.4V	0.027uA
42	746mV	119.9V	0.016uA	747mV	132.3V	0.011uA
43	750mV	129.9V	0.002uA	750mV	125.8V	0.024uA
44	749mV	126.4V	0.033uA	748mV	121.7V	0.042uA
45	746mV	131.1V	0.013uA	750mV	129.4V	0.017uA
46	749mV	128.2V	0.043uA	747mV	131.5V	0.003uA
47	746mV	125.2V	0.003uA	747mV	132.0V	0.007uA
48	749mV	126.2V	0.032uA	750mV	118.0V	0.027uA
49	746mV	117.7V	0.013uA	747mV	133.2V	0.005uA
50	750mV	127.8V	0.024uA	747mV	128.8V	0.045uA
51	749mV	132.1V	0.017uA	750mV	131.3V	0.005uA
52	746mV	131.2V	0.009uA	747mV	118.9V	0.025uA
53	750mV	122.1V	0.013uA	745mV	122.6V	0.032uA
54	747mV	118.7V	0.020uA	750mV	128.0V	0.028uA
55	748mV	125.1V	0.021uA	746mV	120.1V	0.041uA
56	750mV	120.8V	0.039uA	748mV	129.5V	0.009uA
57	750mV	124.3V	0.016uA	747mV	129.1V	0.029uA
58	748mV	121.1V	0.011uA	747mV	121.2V	0.019uA
59	750mV	125.8V	0.024uA	748mV	127.8V	0.023uA
60	748mV	121.2V	0.045uA	750mV	124.4V	0.039uA



## High Temperature Storage Life Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	747mV	124.2V	0.022uA	749mV	122.5V	0.021uA
62	748mV	119.6V	0.022uA	750mV	117.2V	0.034uA
63	746mV	130.8V	0.034uA	750mV	121.2V	0.014uA
64	748mV	132.6V	0.004uA	748mV	117.5V	0.022uA
65	748mV	130.1V	0.023uA	749mV	118.6V	0.042uA
66	749mV	121.1V	0.003uA	750mV	131.9V	0.015uA
67	748mV	126.8V	0.008uA	747mV	131.8V	0.029uA
68	750mV	123.3V	0.015uA	749mV	123.6V	0.015uA
69	748mV	123.5V	0.013uA	745mV	119.3V	0.039uA
70	745mV	121.3V	0.037uA	750mV	126.4V	0.012uA
71	748mV	125.2V	0.025uA	746mV	119.1V	0.012uA
72	749mV	128.7V	0.002uA	749mV	117.1V	0.044uA
73	747mV	118.9V	0.010uA	749mV	119.1V	0.011uA
74	749mV	132.4V	0.029uA	748mV	128.9V	0.006uA
75	750mV	127.1V	0.043uA	748mV	119.8V	0.007uA
76	748mV	120.0V	0.034uA	750mV	116.9V	0.006uA
77	749mV	124.1V	0.023uA	746mV	124.8V	0.026uA

Made By: Leo Hsia

Approval: Peter Yang



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	746mV	131.1V	0.035uA	746mV	130.3V	0.026uA
2	749mV	132.9V	0.016uA	750mV	117.5V	0.020uA
3	747mV	122.0V	0.035uA	748mV	123.7V	0.037uA
4	749mV	123.3V	0.039uA	745mV	123.2V	0.031uA
5	746mV	131.4V	0.025uA	749mV	118.8V	0.009uA
6	746mV	120.5V	0.026uA	746mV	123.8V	0.013uA
7	746mV	126.7V	0.010uA	750mV	117.1V	0.021uA
8	747mV	129.9V	0.008uA	750mV	120.7V	0.006uA
9	748mV	121.1V	0.003uA	748mV	131.4V	0.016uA
10	748mV	122.1V	0.035uA	746mV	130.4V	0.037uA
11	749mV	118.3V	0.031uA	746mV	129.0V	0.015uA
12	750mV	125.0V	0.043uA	748mV	118.3V	0.023uA
13	745mV	129.0V	0.031uA	747mV	120.2V	0.010uA
14	746mV	124.0V	0.025uA	749mV	117.7V	0.036uA
15	746mV	130.6V	0.035uA	750mV	132.9V	0.024uA
16	747mV	133.1V	0.026uA	748mV	122.3V	0.016uA
17	746mV	125.5V	0.042uA	748mV	120.2V	0.011uA
18	749mV	131.3V	0.014uA	750mV	119.9V	0.029uA
19	750mV	119.6V	0.010uA	750mV	126.2V	0.021uA
20	748mV	125.0V	0.034uA	749mV	119.5V	0.031uA
21	750mV	127.0V	0.026uA	747mV	118.5V	0.044uA
22	745mV	118.0V	0.023uA	747mV	124.3V	0.035uA
23	750mV	128.7V	0.029uA	750mV	132.6V	0.032uA
24	750mV	129.5V	0.041uA	748mV	117.6V	0.045uA
25	749mV	122.3V	0.027uA	747mV	122.6V	0.024uA
26	750mV	128.8V	0.005uA	746mV	125.7V	0.028uA
27	750mV	122.4V	0.033uA	748mV	124.2V	0.017uA
28	750mV	123.0V	0.018uA	745mV	124.3V	0.005uA
29	749mV	124.2V	0.008uA	745mV	129.7V	0.024uA
30	748mV	125.1V	0.012uA	745mV	126.4V	0.013uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	750mV	118.7V	0.013uA	748mV	124.4V	0.020uA
32	749mV	124.5V	0.004uA	749mV	124.0V	0.020uA
33	745mV	119.5V	0.036uA	746mV	125.3V	0.030uA
34	749mV	124.7V	0.035uA	750mV	130.4V	0.023uA
35	746mV	119.2V	0.003uA	749mV	121.4V	0.030uA
36	749mV	125.4V	0.030uA	747mV	130.8V	0.020uA
37	748mV	117.0V	0.041uA	747mV	120.1V	0.003uA
38	746mV	127.4V	0.028uA	750mV	131.6V	0.037uA
39	747mV	131.6V	0.036uA	749mV	125.7V	0.035uA
40	747mV	127.9V	0.035uA	747mV	126.0V	0.044uA
41	749mV	119.6V	0.013uA	748mV	118.5V	0.018uA
42	749mV	128.7V	0.025uA	747mV	121.1V	0.012uA
43	749mV	125.0V	0.017uA	746mV	122.2V	0.004uA
44	748mV	124.8V	0.017uA	748mV	127.0V	0.021uA
45	750mV	121.6V	0.025uA	749mV	117.2V	0.006uA
46	749mV	131.7V	0.011uA	749mV	132.6V	0.015uA
47	750mV	123.6V	0.019uA	750mV	129.5V	0.012uA
48	748mV	127.6V	0.039uA	746mV	120.6V	0.041uA
49	748mV	131.9V	0.040uA	747mV	125.7V	0.022uA
50	746mV	121.3V	0.029uA	746mV	125.7V	0.015uA
51	746mV	121.7V	0.008uA	747mV	122.7V	0.032uA
52	745mV	121.2V	0.014uA	747mV	120.0V	0.042uA
53	747mV	121.7V	0.032uA	750mV	125.3V	0.022uA
54	750mV	119.2V	0.005uA	746mV	123.4V	0.031uA
55	748mV	119.6V	0.006uA	750mV	128.5V	0.041uA
56	747mV	132.4V	0.014uA	746mV	129.8V	0.016uA
57	750mV	131.4V	0.040uA	746mV	126.4V	0.044uA
58	750mV	130.4V	0.036uA	749mV	124.2V	0.044uA
59	750mV	130.3V	0.011uA	749mV	121.1V	0.044uA
60	747mV	123.5V	0.039uA	747mV	133.0V	0.028uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	748mV	121.9V	0.026uA	748mV	123.3V	0.023uA
62	748mV	129.5V	0.014uA	749mV	118.9V	0.017uA
63	746mV	126.0V	0.042uA	746mV	132.8V	0.023uA
64	748mV	117.7V	0.019uA	748mV	123.2V	0.032uA
65	747mV	125.9V	0.028uA	749mV	132.9V	0.019uA
66	746mV	126.3V	0.024uA	747mV	126.0V	0.016uA
67	748mV	126.5V	0.015uA	750mV	127.1V	0.014uA
68	750mV	126.4V	0.007uA	749mV	120.6V	0.010uA
69	747mV	124.5V	0.011uA	747mV	125.0V	0.043uA
70	747mV	117.8V	0.023uA	749mV	121.0V	0.042uA
71	749mV	117.9V	0.030uA	750mV	130.3V	0.024uA
72	748mV	119.1V	0.016uA	747mV	127.8V	0.016uA
73	748mV	125.4V	0.005uA	749mV	121.8V	0.026uA
74	750mV	118.6V	0.036uA	748mV	122.0V	0.007uA
75	747mV	119.7V	0.007uA	745mV	127.3V	0.038uA
76	747mV	118.4V	0.039uA	749mV	117.0V	0.028uA
77	745mV	128.8V	0.005uA	748mV	122.0V	0.020uA

Made By: Leo Hsia

Approval: Peter Yang



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	747mV	127.4V	0.026uA	746mV	128.1V	0.010uA
2	749mV	119.1V	0.010uA	747mV	132.9V	0.037uA
3	747mV	132.9V	0.017uA	745mV	129.3V	0.019uA
4	747mV	120.7V	0.027uA	746mV	125.9V	0.013uA
5	747mV	124.5V	0.036uA	746mV	130.8V	0.021uA
6	750mV	117.5V	0.012uA	745mV	120.8V	0.035uA
7	746mV	123.1V	0.006uA	747mV	128.0V	0.015uA
8	750mV	130.9V	0.006uA	745mV	121.2V	0.043uA
9	749mV	118.4V	0.035uA	748mV	132.8V	0.012uA
10	749mV	122.2V	0.029uA	746mV	127.1V	0.026uA
11	748mV	132.7V	0.017uA	750mV	127.2V	0.033uA
12	747mV	123.8V	0.030uA	746mV	128.9V	0.037uA
13	747mV	121.0V	0.013uA	747mV	119.8V	0.002uA
14	749mV	125.5V	0.031uA	746mV	124.3V	0.017uA
15	746mV	127.0V	0.007uA	748mV	125.9V	0.043uA
16	750mV	128.4V	0.013uA	747mV	132.1V	0.044uA
17	745mV	125.5V	0.011uA	747mV	118.9V	0.035uA
18	746mV	123.5V	0.043uA	746mV	132.2V	0.010uA
19	746mV	125.9V	0.007uA	749mV	123.2V	0.044uA
20	750mV	131.6V	0.034uA	748mV	119.6V	0.034uA
21	746mV	125.2V	0.031uA	747mV	132.7V	0.039uA
22	749mV	127.9V	0.012uA	749mV	124.1V	0.033uA
23	748mV	119.1V	0.042uA	750mV	122.3V	0.041uA
24	748mV	122.9V	0.004uA	749mV	126.0V	0.002uA
25	749mV	124.3V	0.039uA	745mV	131.5V	0.022uA
26	746mV	130.0V	0.035uA	746mV	128.7V	0.026uA
27	748mV	117.3V	0.011uA	750mV	118.8V	0.038uA
28	749mV	117.4V	0.044uA	748mV	119.0V	0.041uA
29	746mV	127.6V	0.039uA	745mV	123.7V	0.034uA
30	747mV	123.2V	0.025uA	747mV	122.7V	0.031uA





# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	746mV	117.1V	0.045uA	748mV	128.1V	0.027uA
32	746mV	131.3V	0.002uA	748mV	118.3V	0.041uA
33	747mV	122.0V	0.038uA	746mV	131.1V	0.036uA
34	747mV	119.6V	0.007uA	748mV	129.0V	0.007uA
35	749mV	117.5V	0.011uA	749mV	123.6V	0.030uA
36	749mV	121.0V	0.033uA	746mV	127.5V	0.002uA
37	750mV	124.5V	0.030uA	749mV	125.9V	0.012uA
38	748mV	122.1V	0.023uA	746mV	128.3V	0.014uA
39	748mV	122.1V	0.019uA	748mV	121.4V	0.031uA
40	750mV	124.9V	0.032uA	750mV	126.2V	0.020uA
41	748mV	121.6V	0.036uA	748mV	130.3V	0.035uA
42	749mV	131.7V	0.015uA	748mV	130.2V	0.034uA
43	750mV	131.9V	0.034uA	746mV	121.9V	0.036uA
44	750mV	119.7V	0.020uA	747mV	118.1V	0.023uA
45	749mV	120.4V	0.031uA	747mV	122.8V	0.028uA
46	750mV	133.0V	0.033uA	748mV	124.1V	0.003uA
47	748mV	123.0V	0.010uA	749mV	118.1V	0.016uA
48	750mV	120.0V	0.009uA	750mV	132.5V	0.019uA
49	748mV	131.6V	0.018uA	745mV	124.1V	0.005uA
50	747mV	120.2V	0.034uA	749mV	132.2V	0.017uA
51	746mV	125.7V	0.032uA	747mV	128.0V	0.038uA
52	748mV	124.0V	0.018uA	747mV	128.8V	0.035uA
53	750mV	117.1V	0.019uA	746mV	119.5V	0.041uA
54	748mV	124.8V	0.017uA	747mV	127.4V	0.018uA
55	748mV	132.8V	0.026uA	747mV	121.5V	0.018uA
56	749mV	131.1V	0.037uA	746mV	123.5V	0.021uA
57	745mV	124.9V	0.003uA	746mV	119.6V	0.031uA
58	745mV	129.3V	0.034uA	747mV	131.5V	0.002uA
59	750mV	132.8V	0.010uA	749mV	118.9V	0.012uA
60	750mV	116.9V	0.024uA	748mV	124.6V	0.022uA



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	746mV	129.4V	0.012uA	750mV	130.0V	0.035uA
62	747mV	124.0V	0.043uA	747mV	130.5V	0.005uA
63	746mV	117.7V	0.003uA	746mV	129.0V	0.035uA
64	750mV	125.1V	0.044uA	745mV	125.0V	0.030uA
65	747mV	128.9V	0.028uA	746mV	117.8V	0.018uA
66	749mV	131.9V	0.020uA	749mV	122.0V	0.031uA
67	747mV	118.8V	0.007uA	748mV	132.3V	0.040uA
68	747mV	130.7V	0.033uA	748mV	126.9V	0.034uA
69	750mV	125.3V	0.012uA	746mV	130.3V	0.025uA
70	746mV	126.1V	0.013uA	749mV	117.3V	0.033uA
71	749mV	122.8V	0.033uA	750mV	121.9V	0.036uA
72	750mV	117.9V	0.006uA	746mV	127.3V	0.006uA
73	748mV	122.7V	0.008uA	746mV	124.7V	0.042uA
74	746mV	117.9V	0.024uA	750mV	121.4V	0.014uA
75	746mV	117.1V	0.008uA	745mV	119.0V	0.014uA
76	746mV	131.4V	0.009uA	748mV	118.1V	0.014uA
77	748mV	127.4V	0.020uA	749mV	117.2V	0.018uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temperature High Humidity Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	749mV	120.4V	0.040uA	750mV	132.6V	0.023uA
2	749mV	119.0V	0.033uA	750mV	126.7V	0.037uA
3	745mV	131.9V	0.040uA	749mV	120.7V	0.032uA
4	746mV	130.1V	0.013uA	745mV	133.0V	0.040uA
5	746mV	128.6V	0.033uA	750mV	124.5V	0.017uA
6	748mV	130.1V	0.019uA	749mV	130.6V	0.014uA
7	749mV	126.2V	0.008uA	748mV	131.5V	0.018uA
8	747mV	117.7V	0.004uA	749mV	131.4V	0.009uA
9	747mV	133.0V	0.019uA	750mV	120.8V	0.036uA
10	746mV	118.8V	0.041uA	750mV	124.2V	0.017uA
11	748mV	122.5V	0.016uA	750mV	128.9V	0.040uA
12	747mV	129.5V	0.020uA	750mV	130.1V	0.005uA
13	748mV	130.2V	0.022uA	750mV	130.8V	0.010uA
14	746mV	118.5V	0.035uA	749mV	132.9V	0.015uA
15	750mV	128.3V	0.039uA	747mV	120.2V	0.040uA
16	749mV	126.5V	0.026uA	746mV	127.3V	0.039uA
17	750mV	128.1V	0.036uA	747mV	132.8V	0.034uA
18	748mV	128.2V	0.008uA	749mV	121.3V	0.011uA
19	746mV	128.3V	0.009uA	746mV	128.3V	0.025uA
20	746mV	127.5V	0.026uA	750mV	120.4V	0.014uA
21	747mV	132.9V	0.041uA	748mV	119.5V	0.040uA
22	746mV	119.8V	0.004uA	749mV	117.8V	0.027uA
23	747mV	129.5V	0.021uA	747mV	132.1V	0.014uA
24	750mV	117.5V	0.042uA	746mV	120.9V	0.027uA
25	745mV	118.0V	0.006uA	750mV	121.2V	0.004uA
26	750mV	121.9V	0.015uA	748mV	132.3V	0.014uA
27	746mV	129.9V	0.023uA	745mV	121.9V	0.011uA
28	745mV	125.0V	0.010uA	747mV	129.8V	0.012uA
29	750mV	132.9V	0.025uA	750mV	132.2V	0.035uA
30	745mV	118.7V	0.009uA	747mV	117.7V	0.021uA



## High Temperature High Humidity Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	750mV	127.8V	0.031uA	747mV	120.3V	0.037uA
32	747mV	129.0V	0.011uA	749mV	129.4V	0.042uA
33	747mV	125.6V	0.027uA	745mV	132.9V	0.038uA
34	749mV	126.6V	0.010uA	750mV	117.8V	0.025uA
35	746mV	132.5V	0.033uA	746mV	117.0V	0.008uA
36	747mV	126.6V	0.037uA	745mV	124.4V	0.014uA
37	746mV	123.7V	0.025uA	749mV	117.4V	0.036uA
38	747mV	123.4V	0.033uA	748mV	128.4V	0.029uA
39	749mV	118.2V	0.038uA	748mV	120.4V	0.045uA
40	746mV	122.7V	0.034uA	749mV	117.6V	0.019uA
41	746mV	127.4V	0.023uA	745mV	121.6V	0.024uA
42	746mV	132.1V	0.011uA	750mV	118.1V	0.036uA
43	749mV	122.5V	0.037uA	749mV	129.4V	0.016uA
44	745mV	119.2V	0.031uA	746mV	131.9V	0.037uA
45	747mV	125.5V	0.008uA	750mV	117.3V	0.002uA
46	748mV	122.0V	0.010uA	750mV	120.6V	0.011uA
47	750mV	122.6V	0.007uA	746mV	125.0V	0.024uA
48	749mV	117.2V	0.010uA	747mV	129.2V	0.024uA
49	746mV	122.3V	0.015uA	749mV	131.4V	0.009uA
50	747mV	124.3V	0.037uA	747mV	118.2V	0.028uA
51	748mV	120.0V	0.023uA	745mV	130.0V	0.017uA
52	749mV	120.0V	0.011uA	749mV	124.6V	0.016uA
53	747mV	125.6V	0.016uA	750mV	132.3V	0.034uA
54	748mV	125.5V	0.013uA	747mV	130.6V	0.014uA
55	749mV	124.0V	0.043uA	750mV	117.5V	0.040uA
56	746mV	119.6V	0.036uA	748mV	125.9V	0.025uA
57	749mV	124.9V	0.015uA	749mV	120.0V	0.015uA
58	750mV	125.8V	0.033uA	746mV	118.6V	0.043uA
59	746mV	132.7V	0.044uA	748mV	130.3V	0.007uA
60	749mV	128.5V	0.025uA	747mV	121.7V	0.022uA



## High Temperature High Humidity Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	750mV	120.8V	0.034uA	746mV	121.7V	0.037uA
62	747mV	124.9V	0.033uA	746mV	120.6V	0.015uA
63	749mV	126.3V	0.003uA	747mV	123.4V	0.023uA
64	749mV	130.9V	0.010uA	747mV	132.6V	0.042uA
65	750mV	122.3V	0.037uA	749mV	121.8V	0.035uA
66	749mV	132.4V	0.044uA	749mV	128.0V	0.030uA
67	748mV	127.0V	0.017uA	746mV	133.2V	0.042uA
68	746mV	118.6V	0.031uA	746mV	131.6V	0.012uA
69	747mV	127.7V	0.012uA	749mV	123.3V	0.033uA
70	747mV	117.6V	0.011uA	746mV	120.6V	0.041uA
71	749mV	122.8V	0.035uA	746mV	120.1V	0.016uA
72	747mV	126.0V	0.040uA	746mV	118.4V	0.017uA
73	748mV	124.6V	0.018uA	746mV	132.0V	0.016uA
74	750mV	125.5V	0.011uA	748mV	130.0V	0.029uA
75	749mV	121.3V	0.017uA	747mV	118.9V	0.044uA
76	746mV	125.6V	0.034uA	750mV	124.3V	0.029uA
77	748mV	118.4V	0.032uA	748mV	124.4V	0.040uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temper High Humidity Reverse Bies Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	750mV	119.9V	0.018uA	745mV	125.7V	0.006uA
2	750mV	130.9V	0.020uA	749mV	119.5V	0.035uA
3	747mV	123.9V	0.041uA	747mV	124.0V	0.039uA
4	746mV	133.0V	0.014uA	749mV	118.5V	0.006uA
5	750mV	120.7V	0.020uA	748mV	132.6V	0.003uA
6	750mV	117.4V	0.014uA	748mV	133.0V	0.008uA
7	749mV	132.3V	0.016uA	746mV	128.0V	0.008uA
8	748mV	133.2V	0.030uA	748mV	130.6V	0.025uA
9	749mV	128.0V	0.026uA	749mV	130.9V	0.008uA
10	745mV	125.1V	0.024uA	749mV	131.1V	0.028uA
11	747mV	122.0V	0.020uA	750mV	123.9V	0.042uA
12	747mV	118.3V	0.026uA	745mV	128.7V	0.032uA
13	748mV	132.3V	0.041uA	746mV	121.3V	0.003uA
14	750mV	132.0V	0.018uA	746mV	132.5V	0.022uA
15	746mV	120.8V	0.034uA	746mV	120.3V	0.029uA
16	747mV	121.3V	0.030uA	750mV	122.8V	0.023uA
17	749mV	131.4V	0.010uA	747mV	131.9V	0.029uA
18	746mV	127.3V	0.014uA	750mV	119.0V	0.008uA
19	748mV	121.7V	0.023uA	746mV	119.6V	0.007uA
20	747mV	118.8V	0.043uA	750mV	126.3V	0.006uA
21	745mV	131.7V	0.004uA	750mV	126.8V	0.017uA
22	748mV	118.2V	0.004uA	748mV	132.9V	0.024uA
23	747mV	130.8V	0.026uA	749mV	125.6V	0.037uA
24	746mV	130.1V	0.036uA	746mV	129.4V	0.016uA
25	746mV	127.1V	0.017uA	746mV	128.3V	0.042uA
26	747mV	130.0V	0.039uA	749mV	122.6V	0.015uA
27	746mV	121.0V	0.041uA	750mV	129.2V	0.005uA
28	745mV	117.5V	0.045uA	750mV	130.7V	0.042uA
29	745mV	127.3V	0.033uA	750mV	132.4V	0.007uA
30	749mV	123.5V	0.035uA	750mV	119.7V	0.024uA



## High Temper High Humidity Reverse Bies Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	750mV	119.1V	0.025uA	747mV	117.8V	0.040uA
32	749mV	117.7V	0.020uA	749mV	124.6V	0.017uA
33	746mV	126.5V	0.012uA	750mV	123.4V	0.014uA
34	745mV	119.7V	0.032uA	749mV	119.8V	0.004uA
35	747mV	124.5V	0.029uA	746mV	130.6V	0.017uA
36	748mV	126.2V	0.020uA	749mV	124.2V	0.029uA
37	747mV	127.7V	0.043uA	747mV	118.8V	0.036uA
38	748mV	124.6V	0.039uA	745mV	127.9V	0.032uA
39	748mV	130.5V	0.013uA	747mV	117.5V	0.038uA
40	748mV	122.4V	0.005uA	747mV	120.3V	0.036uA
41	745mV	118.7V	0.006uA	746mV	122.2V	0.037uA
42	747mV	120.2V	0.032uA	747mV	128.5V	0.019uA
43	747mV	131.6V	0.035uA	749mV	121.8V	0.034uA
44	749mV	121.9V	0.015uA	746mV	130.7V	0.019uA
45	746mV	124.3V	0.024uA	746mV	124.0V	0.013uA
46	749mV	130.5V	0.040uA	748mV	117.2V	0.027uA
47	747mV	125.7V	0.026uA	749mV	122.9V	0.038uA
48	749mV	125.3V	0.029uA	748mV	130.0V	0.028uA
49	746mV	119.4V	0.035uA	746mV	117.9V	0.028uA
50	746mV	132.4V	0.025uA	749mV	132.0V	0.033uA
51	748mV	127.4V	0.022uA	747mV	132.8V	0.040uA
52	745mV	120.7V	0.011uA	749mV	123.0V	0.026uA
53	749mV	123.4V	0.039uA	749mV	120.9V	0.031uA
54	748mV	125.4V	0.010uA	749mV	131.2V	0.030uA
55	746mV	125.7V	0.029uA	750mV	118.1V	0.006uA
56	746mV	126.3V	0.005uA	746mV	125.0V	0.013uA
57	750mV	129.9V	0.037uA	746mV	128.3V	0.028uA
58	746mV	124.4V	0.013uA	746mV	127.4V	0.037uA
59	747mV	120.0V	0.039uA	746mV	131.7V	0.003uA
60	748mV	128.1V	0.030uA	750mV	127.2V	0.019uA



## High Temper High Humidity Reverse Bies Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	750mV	124.7V	0.003uA	747mV	127.5V	0.018uA
62	750mV	125.1V	0.028uA	750mV	121.8V	0.003uA
63	746mV	123.5V	0.018uA	750mV	130.4V	0.029uA
64	749mV	122.2V	0.022uA	750mV	131.0V	0.008uA
65	746mV	123.8V	0.026uA	745mV	129.1V	0.020uA
66	750mV	129.0V	0.029uA	750mV	127.8V	0.015uA
67	748mV	119.8V	0.012uA	748mV	133.0V	0.017uA
68	746mV	126.9V	0.025uA	746mV	131.6V	0.014uA
69	745mV	125.3V	0.004uA	748mV	124.3V	0.013uA
70	746mV	129.5V	0.029uA	747mV	123.8V	0.013uA
71	749mV	131.9V	0.042uA	745mV	123.6V	0.008uA
72	746mV	126.4V	0.003uA	749mV	128.5V	0.042uA
73	748mV	129.9V	0.005uA	746mV	128.1V	0.020uA
74	748mV	130.9V	0.004uA	750mV	131.2V	0.038uA
75	748mV	132.8V	0.011uA	749mV	126.4V	0.006uA
76	746mV	131.2V	0.013uA	746mV	130.2V	0.037uA
77	749mV	122.3V	0.038uA	746mV	124.4V	0.027uA

Made By: Leo Hsia

Approval: Peter Yang





# SeCoS Corporation

## Solderability Test Data

Report No : T140630-035

Part No : BAS16

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<855mV@IF=10mA, VB>75V@I=0.1mA, IR<1uA@VR=75V

Test Condition: 245°C ± 5°C, 5Sec

Test Date: 2014.06.28 ~ 2014.06.28

Test Standard : JESD22 STANDER Method-B102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	745mV	130.4V	0.024uA	749mV	131.3V	0.009uA
2	746mV	130.9V	0.032uA	749mV	117.0V	0.035uA
3	748mV	126.5V	0.013uA	747mV	126.1V	0.016uA
4	746mV	128.4V	0.010uA	747mV	128.0V	0.021uA
5	748mV	121.6V	0.040uA	748mV	118.8V	0.027uA
6	749mV	123.1V	0.042uA	746mV	127.3V	0.008uA
7	748mV	120.9V	0.006uA	749mV	118.3V	0.022uA
8	747mV	127.1V	0.006uA	749mV	127.6V	0.017uA
9	748mV	125.5V	0.032uA	749mV	128.2V	0.019uA
10	750mV	124.4V	0.037uA	748mV	131.4V	0.025uA

Made By: Leo Hsia

Approval: Peter Yang